

Beam size measurement via vertical polarization component of SR at KEKB?

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Background

- Swiss Light Source measured beam sizes $<10 \mu\text{m}$ using vertical polarization component of SR
 - A. Andersson et al., NIMPR A 591 (2008) 437-446
- Question was asked: can this technique be used at KEKB?

A. Andersson et al. / Nuclear Instruments and Methods in Physics Research A 591 (2008) 437–446

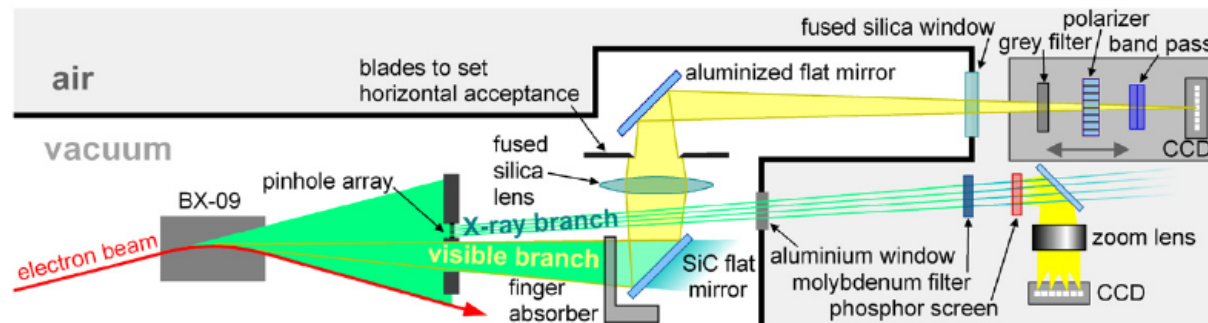
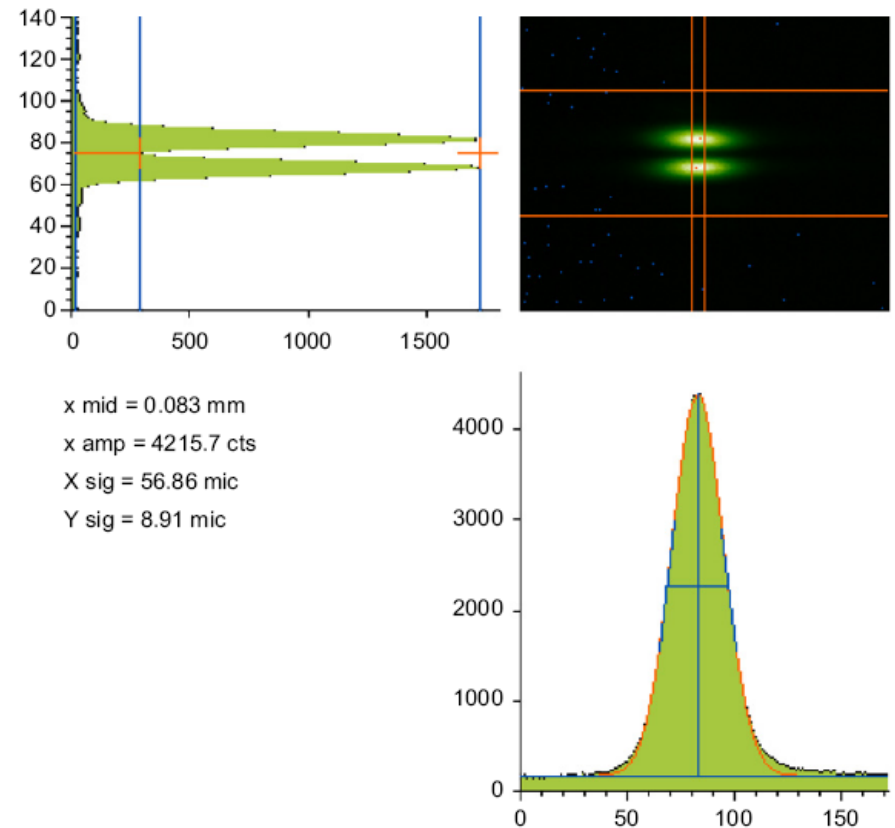


Fig. 1. Top view of the diagnostic beamline, showing the X-ray branch with pinhole array and the vis-UV branch.

Principle

- Vertical polarization component of SR has two peaks in vertical angular axis, goes to zero in middle for point source.
- Finite-sized source produces smeared distribution, so can measure beam size from peak-valley ratio, similar to interferometer.
- Note: Smearing is greater the closer one gets to the source point:

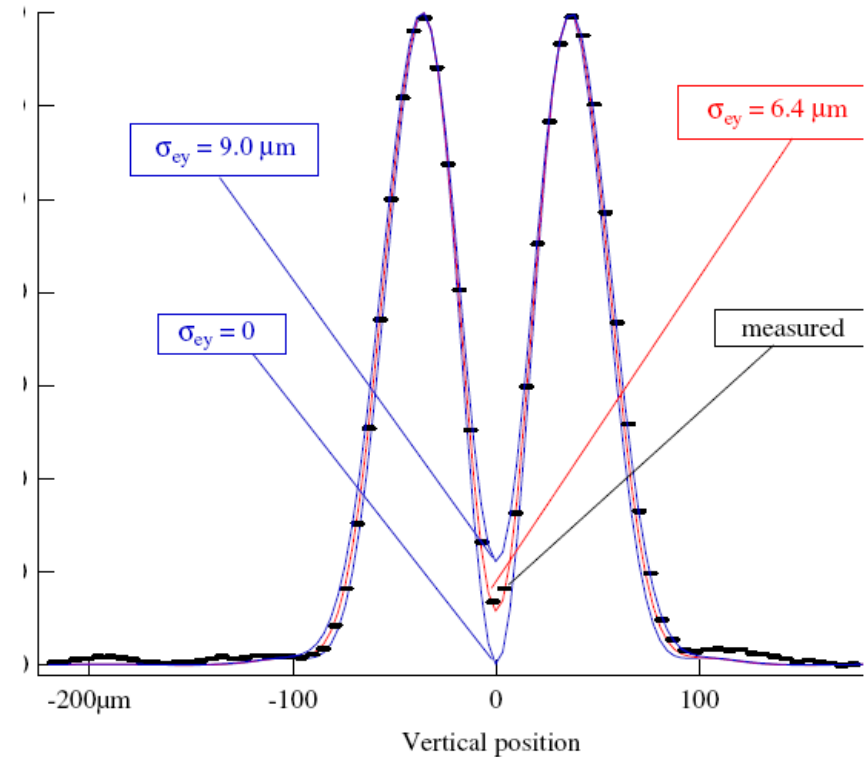
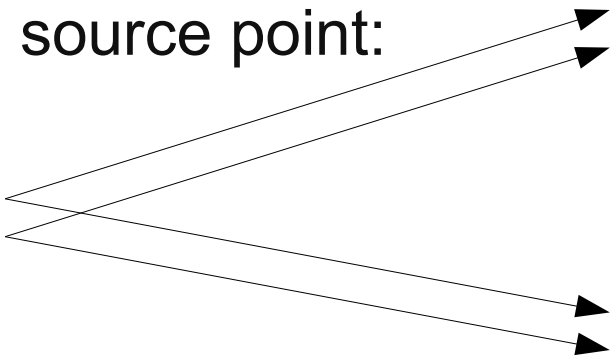


Fig. 8. Measured (marks) and predicted (three solid lines) vertical image profiles. $\lambda = 364 \text{ nm}$; acceptance angles $3.9 \text{ mrad}_H/9.0 \text{ mrad}_V$. Machine conditions: 400 mA in top-up operation; tuned skew quads.

$$E_{\pi}(x, y) = E_{\pi 0} \text{sinc}\left(\frac{2\pi x_c}{\lambda p'} x\right) \times \int_0^{+\infty} (1 + \xi^2)^{1/2} \xi K_{1/3}\left(\frac{1}{2} \frac{\lambda_c}{\lambda} (1 + \xi^2)^{3/2}\right) \sin\left(\frac{2\pi p}{\lambda \gamma p'} y \xi\right) d\xi \quad (1)$$

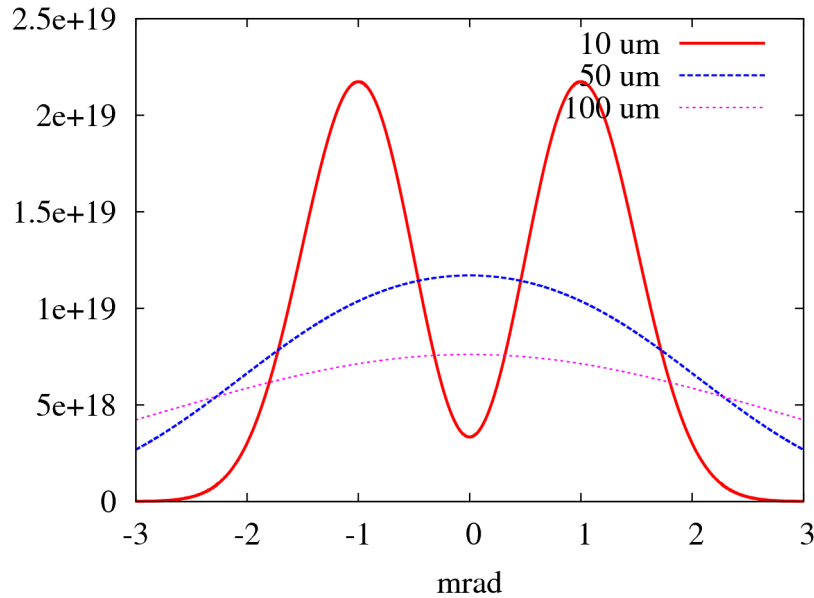
KEKB LER

- Using Kim (AIP 184 (1989)), Eq. 3.12:

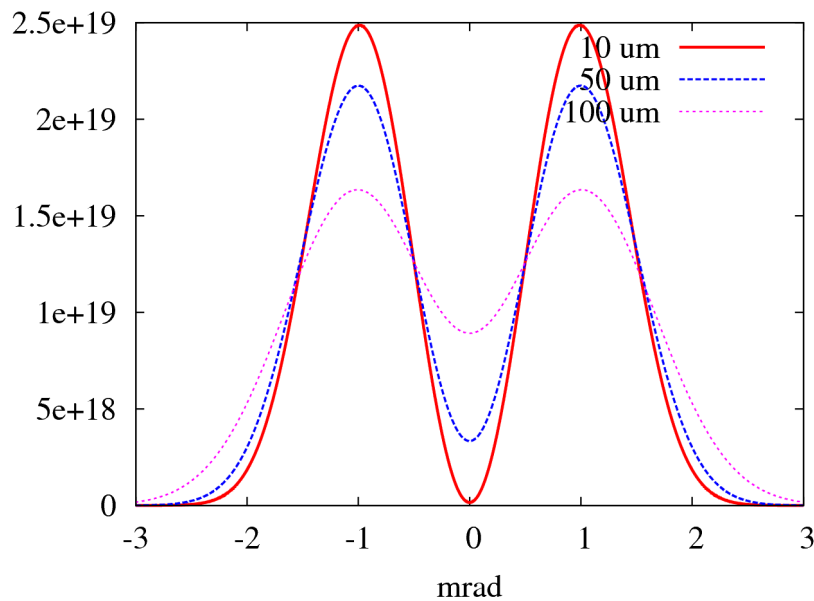
$$\frac{dF}{d\Omega} = \frac{3\alpha}{4\pi^2} \gamma^2 \frac{\Delta\omega}{\omega} \frac{I}{e} \left(\frac{\omega}{\omega_c}\right)^2 (1+X^2) X^2 K_{1/3}^2(\eta)$$

$$X = \gamma\psi; \eta = \frac{1}{2} \frac{\omega}{\omega_c} (1+X^2)^{3/2}$$

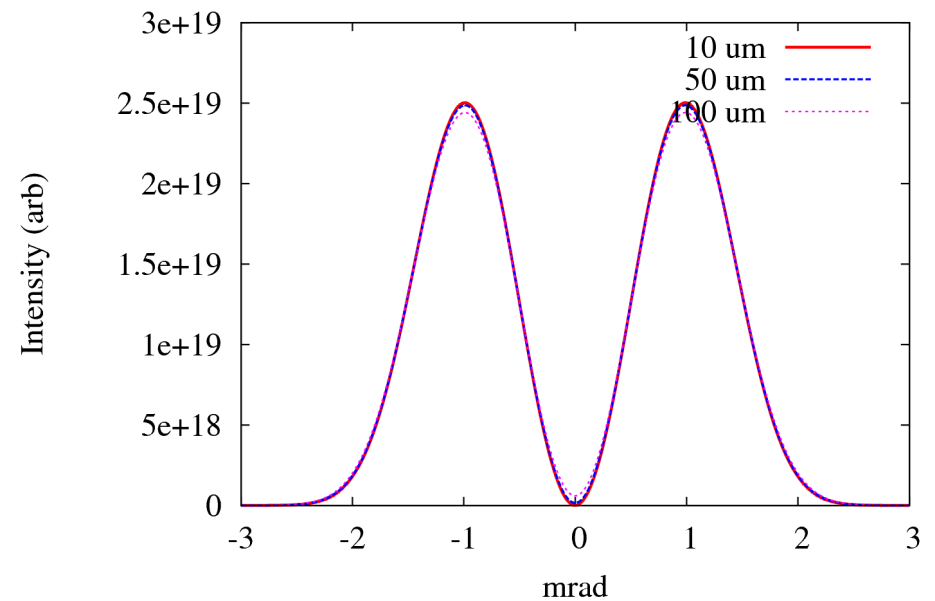
LER (L=40 mm)



LER (L=200 mm)

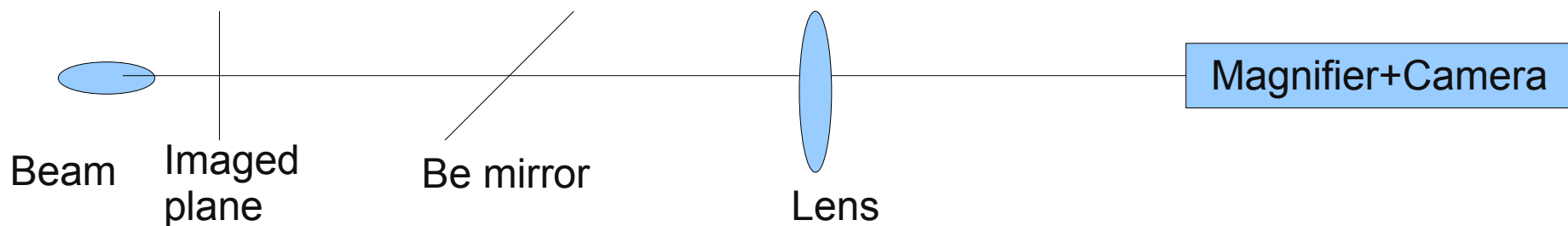


LER (L=1000 mm)



KEKB LER (cont).

- Measurement is in principle possible at current KEBB LER.
- Requires imaging point 200 mm downstream of source point.
- How to calibrate?
 - Beryllium mirror distortion will change focal length
 - One possibility: with camera (and magnifier) on movable stage, can find beam source position and Be mirror position. Then interpolate.



Error estimate

- $1/f = 1/p + 1/p'$
 - f = focal length of lens
 - p' = lens-camera distance
 - p = imaged plane to lens distance
 - Note: beam to lens \approx 60 m (LER2)
- For $f = 1$ m:
 - Beam focuses at $p' = 1.017$ m
 - Be mirror focuses at $p' = 1.026$ m
 - If we have a stage which can cover 1 cm with 1 μ m accuracy, then a 1 μ m error in p' translates to a 3.5 mm error in p . This is 2% of the 20 cm distance from beam.
- Note: A 1 cm source depth (5% of beam-imaged plane distance, similar to Swiss Light Source), requires a 1 cm-wide aperture at 60 m. This is reasonable.

Summary

- The measurement is in principle doable at present KEKB.
- Mirror distortion will introduce a huge beam current dependence, so this would not be usable as a daily monitor without heat-distortion-free optics.
- It could potentially be useful as a cross-check.